Byesim: a tool for fast device characterization with Bayesian inference

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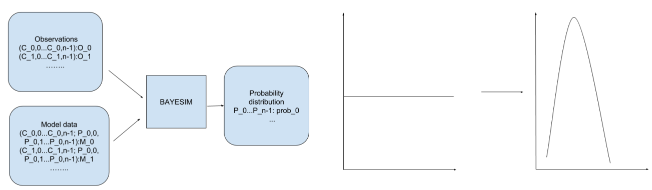
abstract abstract

INTRODUCTION

MODEL

SOFTWARE ARCHITECTURE

Figure 1: detailed workflow (including iteration to update posterior)



(a) (b)

FIG. 1. (a) Scheme (b) Probability

EXAMPLE WITH DIODE - VALIDATION

Figure 2: diode fit stuff

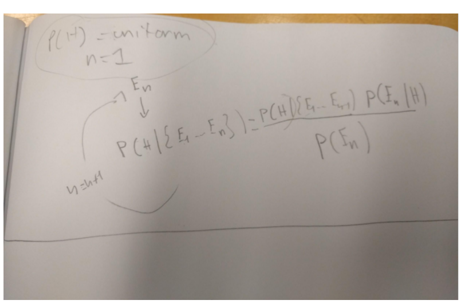


FIG. 2. Bayesian workflow

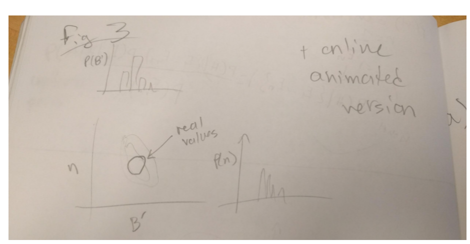
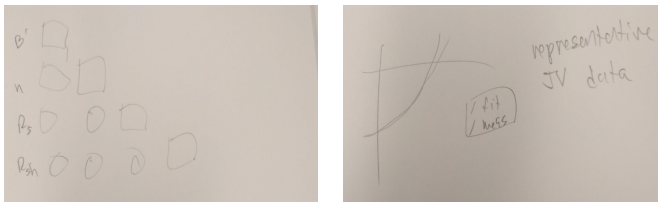


FIG. 3. Ideal diode

EXAMPLE WITH REAL DATA

Figure 4: fitting real data (maybe resistive diode?)



(a) (b)

FIG. 4. Real data

DISCUSSION

CONCLUSIONS

ACKNOWLEDGEMENTS

APPENDIX

include minimal code to run diode example

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